

INVENTOR: PLANKI, Peter et al.
Serial No. 10/070,528

IN THE CLAIMS

1. (Currently Amended) Method for an automated monitoring and controlling the operational performance of a computer or processor system (1) comprising the following steps:

(a) detecting directly at least two parameters of individual components of the computer or processor system (1), wherein at least one of said individual components is ancillary to a processor of the computer or processor system, **and wherein said at least two parameters are parameters that relate to failures of said individual components;**

(b) comparing the detected parameters with predetermined limit values;

(c) determining, if predetermined limit values are exceeded or fallen below of by one or several of said detected parameters;

(d) determining an operational event on basis of said limit values that have been exceeded or fallen below of;

(e) selecting a reaction corresponding to said determined operational event from a number of predetermined reaction patterns, wherein said number of predetermined reaction patterns includes reactions that control individually each of a plurality of discrete components being monitored to maintain or prolong the serviceability of the monitored system and protect to the greatest possible extent active calculation processes as well as their data bases and results and to avoid damage to the discrete component being controlled by a reaction; and

INVENTOR: PLANKI, Peter et al.
Serial No. 10/070,528

(f) transmitting a control command to alter the operational performance corresponding to said selected reaction to said computer or processor system (1).

2. (Previously Presented) Method of claim 1, characterized in that the detected parameters are absolute measured values as well as the temporal change of said measured value.

3. (Original) Method of one of the preceding claims, characterized in that besides the transmission of the control command corresponding to the selected reaction also a corresponding information signal is transmitted.

4. (Currently Amended) A device for an automated monitoring and controlling the operational performance of a computer or processor system (1), comprising:

first sensors (3) for detecting directly at least two parameters of individual components of said computer or processor system (1), wherein at least one of said individual components is ancillary to a processor of the computer or processor system, **and wherein said at least two parameters are parameters that relate to failures of said individual components.**

a monitoring unit (7) for comparing said detected parameters with limit values stored in a first storage (8) as well as for detecting, if one or several limit values are being exceeded or fallen below of,

means for generating a determined operational event message on basis of said limit values that have been exceeded or fallen below of, and

INVENTOR: PLANKI, Peter et al.
Serial No. 10/070,528

a control unit (9) for receiving said operational event message as well as for selecting and transmitting a control command corresponding to said operational event message to said computer and processor system (1) from a storage (10) containing a number of predetermined reaction patterns, wherein said number of predetermined reaction patterns includes control commands that control a plurality of the individual components being monitored to maintain or prolong the serviceability of the monitored system and protect to the greatest possible extent active calculation processes as well as their data bases and results and to avoid damage to the discrete component being controlled by a control command.

5. (Previously Presented) Device of claim 4, characterized in that said detected parameters are absolute measured values as well as the temporal changes of said measured value.
6. (Original) Device of claim 4 or 5, characterized in that said device further comprises an optical or acoustic output means for outputting a message corresponding to said operational event message and/or said transmitted control command.
7. (Previously Presented) Device of claim 4, characterized in that said device comprises a transmission means (15) for transmitting a message corresponding to said operational event message and/or to said transmitted control command.
8. (Previously Presented) Device of claim 4, characterized in that said device is part of a computer which is separate from the computer or processor system (1) to be monitored.

INVENTOR: PLANKI, Peter et al.
Serial No. 10/070,528

9. (Original) Device of claim 5, characterized in that said device comprises a transmission means (15) for transmitting a message corresponding to said operational event message and/or to said transmitted control command.

10. (Original) Device of claim 6, characterized in that said device comprises a transmission means (15) for transmitting a message corresponding to said operational event message and/or to said transmitted control command.

11. (Original) Device of claim 5, characterized in that said device is part of a computer which is separate from the computer or processor system (1) to be monitored.

12. (Original) Device of claim 6, characterized in that said device is part of a computer which is separate from the computer or processor system (1) to be monitored.

13. (Original) Device of claim 7, characterized in that said device is part of a computer which is separate from the computer or processor system (1) to be monitored.

14. (Original) Device of claim 9, characterized in that said device is part of a computer which is separate from the computer or processor system (1) to be monitored.

15. (Original) Device of claim 10, characterized in that said device is part of a computer which is separate from the computer or processor system (1) to be monitored.

16. (Currently Amended) Method for an automated monitoring and controlling the operational performance of a computer or processor system (1) comprising the following steps:

(a) detecting directly at least two parameters of individual components of the computer or processor system (1), wherein at least one of said individual components is ancillary

INVENTOR: PLANKI, Peter et al.
Serial No. 10/070,528

to a processor of the computer or processor system, and wherein said parameters are quantitatively measurable parameters, **and wherein said at least two parameters are parameters that relate to failures of said individual components;**

(b) comparing the detected parameters with predetermined limit values;

(c) determining, if predetermined limit values are exceeded or fallen below of by one or several of said detected parameters;

(d) determining an operational event on basis of a combined evaluation of said limit values that have been exceeded or fallen below of;

(e) selecting a reaction corresponding to said determined operational event from a number of predetermined reaction patterns wherein said number of predetermined reaction patterns includes reactions that control individually each of a plurality of discrete components being monitored to maintain or prolong the serviceability of the monitored system and protect to the greatest possible extent active calculation processes as well as their data bases and results and to avoid damage to the discrete component being controlled by a reaction; and

(f) transmitting a control command to alter the operational performance corresponding to said selected reaction to said computer or processor system (1).

17. (Original) The device as claimed in claim 4, wherein the device operates separately from the computer or processor system monitored by the device, such that the computer or

INVENTOR: PLANKI, Peter et al.
Serial No. 10/070,528

processor system can be re-activated by the device after the computer or processor system has been shut down.

18. (Previously Presented) Method of claim 1 wherein said parameters comprise operational parameters.

19. (Previously Presented) Method of claim 18 further comprising the step of detecting at least two environmental parameters of environmental components.

20. (Previously Presented) Method of claim 1 wherein said parameters comprise environmental parameters.